IN THE CLAIMS

Please cancel claims 1-11 without prejudice as being drawn to a non-elected invention.

Please cancel claims 14-16 without prejudice as being drawn to another non-elected invention.

Please enter new claims 17-27.

Please enter the pending claims as follows:

1. - 11. (Canceled)

12. (Original)   A method comprising:

    extracting a subset from product features to form a first set of features;

    extracting a small portion from said first set of features to form a template;

    transforming said template into a second set of features by

        rotating said template;

        scaling spaces between features in said template;

        scaling linewidths of features in said template;

    merging said first set and said second set of features to form a test structure.

13. (Original) The method of claim 12 wherein critical dimension (CD) is measured on said first set of features.

14. - 16. (Canceled)

17. (New) The method of claim 12 wherein said test structure has sufficient uniqueness to facilitate successful pattern recognition of its image.

18. (New) The method of claim 12 wherein said second set of features serves to provide sufficient uniqueness to facilitate pattern recognition of said test structure.

19. (New) The method of claim 12 wherein similar test structures that are located near each other may be distinguished by modifying their second set of features.

20. (New) The method of claim 12 wherein said small portion may represent 3 to 15 percent of said first set of features.

21. (New) The method of claim 12 wherein said rotating of said template is in a counterclockwise direction.

22. (New)   The method of claim 12 wherein said rotating of said template is typically in a range of 15 to 55 degrees.

23. (New)   The method of claim 12 wherein said scaling of said spaces between said features in said template is typically in a range of – 0.85 to + 2.00.

24. (New)   The method of claim 12 wherein said scaling of said linewidths of said features in said template is typically in a range of + 0.25 to – 0.25.

25. (New)   The method of claim 12 wherein a buffer zone is added before said merging of said first set and said second set of features to form said test structure.

26. (New)   The method of claim 25 wherein said buffer zone essentially represents a lateral displacement.

27. (New)   The method of claim 12 wherein an average change in pattern factor of said test structure after said scaling of both said spaces and said linewidths should be kept in a range of – 0.15 to + 0.15.